


<b>Search Notes</b>  	<b>Application/Control No.</b>  10591206	<b>Applicant(s)/Patent Under Reexamination</b>  IKEDA, MASAYUKI
	<b>Examiner</b>  Nguyen, Hai V	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	553.1	03/07/2008	HN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (See search history printout report)	03/12/2008	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner